



VORLESUNG WS 2014/2015 PME-3.3

Physical Characterization of Organic and Organic-Inorganic Thin Films

Prof. Dr. M. Stamm, Prof. Dr. E. Zschech

Termin: Dienstag 2. DS (09:20 – 10:50 Uhr) Raum HEM/219, Beginn: 14.10.2014

14.10.2014	No lecture! First lecture will be on 21st October with Prof. Zschech and Prof. Stamm!	
21.10.2014	Nanostructure and organic electronics	Prof. Zschech/ Prof. Stamm
28.10.2014	Mechanical characterization of organic/polymeric materials; basics of contact mechanics and nanoindentation methods	Dr. Kopycinska-Müller
04.11.2014	Atomic force microscopy – the principle of surface characterization; Mechanical characterization of organic materials on nanoscale	Dr. Kopycinska-Müller
11.11.2014	Multi-scale characterization of hybrid organic-inorganic thin films	Prof. Zschech
18.11.2014	X-ray microscopy and tomography – Potentials, limitations new developments	Prof. Zschech
25.11.2014	Nanoscale characterization of materials by Combined use of TEM and Atom Probe Tomography	Prof. Zschech
02.12.2014	Microscopy with soft matter surfaces and organic thin films (TEM, SEM, AFM)	Dr. Formanek
09.12.2014	Wetting and chemical functionalisation of surfaces	Prof. Stamm
16.12.2014	Interfaces between materials and multilayers for organic electronics (adhesion, reflectometry, scattering, TEM/FIB)	Prof. Stamm
06.01.2015	Chemical analysis of surfaces and organic thin films (XPS, SERS, EELS, EDX)	Dr. Simon
13.01.2015	Spectroscopic and structural characterisation of organic thin films and surfaces (IR, Raman, SERS; AFM, SEM, Scatt.)	Prof. Stamm
20.01.2015	Ellipsometry for organic thin films and surfaces	Dr. Eichhorn
27.01.2015	Review of Physical Characterization	Prof. Stamm
03.02.2015	Klausur	Prof. Stamm/ Prof. Zschech